

**IN THE SPECIFICATION:**

Please amend the paragraph beginning on page 1, last line, and extending to page 2, line 4, as follows:

Japanese Laid-Open Patent Publication No. 2000-100880 or Japanese ~~Lain~~ Laid-Open Patent Publication No. 9-49864 discloses a test apparatus which has a BOST or BIST provided between an external test unit and a circuit to be measured and performs an operational test.